

# PCN97009A Data2

## Reliability Testing Summary

---

<b>Technology:</b>	<b>Si Gate CMOS</b>
<b>Device Type:</b>	<b>XC4025E &amp; XC4013E</b>
<b>Package Type:</b>	<b>HQ240 Thermally Enhanced PQFP</b>
<b>Molding Compound:</b>	<b>Sumitomo 7304LC/F</b>

	<b>Pre. Cond.</b> <b>0.0621%</b> 30/60% 192 Hrs. 3 V.P. 219°C	<b>85°C / 85%</b> 1,000 Hrs.	<b>Pressure Pot</b> 96 Hrs. 121°C/2 Atm.	<b>Temp. Cycle</b> 542 Cys. -65°C / +150°C
<b>Combined Started Lot:</b>	1	1	1	1
<b>Combined Completed Lots:</b>	1	1	1	1
<b>Failures:</b>	0	0	0	0
<b>Device on Test:</b>	111	44	45	21
<b>Actual Device Hours / Cycles:</b>	21,312	44,000	4,320	11,382
<b>Mean:</b>	192	1,000	96	542
<b>Physical Dimension:</b>	Passed			
<b>Solderability:</b>	Passed			
<b>Internal Visual:</b>	Passed			
<b>Lead Integrity:</b>	Passed			
<b>Peel Test / X-Ray:</b>	Passed			